AGD-317D

REV.A0.1

Environment Test Report

Report NO: 11P020012

Summary	☑ **Pass** ☐ **Fail** Note : There is/are ___ defect(s) not list in the report, please check it in the DTS Website. ☐ **Pass with Deviation** **Comment:** _____

Issue date	Approval	Test Engineer
2011-06-20	**Jansin Lee**	**Clement Chien**

Test item list

Testing Result

Num	Test item list	Result	Remark
1	Temperature rise test	Pass	
2	Temperature cycle operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

Configuration of EUT

Host :

Item	Device Information	
SYSTEM PC Model / Ver.	AEC-6625 A0.2	
CPU Board	EPIC-QM57 A1.0	
BIOS / Version	AEC-6625 1.0(01/06/2011)	
CPU Type	Intel Celeron P4500 1.87GHz(133x14)	
Memory Type	DSL DDR3-1066 2GB(ELPIDA J1108BDSE-DJ-F)	
SATA HDD	TOSHIBA 2.5” 160GB(MK1665GSX)	
USB DVD-ROM	LITEON DX-20A4PU	
LCD Monitor	AGD-317D	
Operating System	☒ Windows XP Professional English SP3 32 Bit	
DC Adapter	DC Power Input 12V / 5A	
	Chipset Information with XP Professional English SP3 32 Bit Driver Version	
Chipset Software	Intel(R) Chipset Device Software: 9.1.1.1020(2009/08/26)	
North Bridge	N/A	
South Bridge	Intel QM57	
Super IO Chipset	ITE8781F	
VGA Chipset	Intel(R)GMA HD 6.14.10.5179(2009/11/9)	
Audio Chipset	VIA VT1708B 6.0.1.7300 (2009/07/10)	
Ethernet Chipset	Intel(R)82577LM Gigabit 11.2.19.0(2009/09/23) Intel(R)82574L Gigabit 11.1. 6.0(2009/07/13)	

Num	Item	Spec
1.	**System**:	AGD-317D
	1.A/D Board	ONYX S2523BVL Rev : 0V
	2. Panel	AUO 17” SXGA(1280*1024) TFT LCD Display
	3. Touch Board	EETI S5000CEGG Rev : V1.08D1
	4. Inverter Board	QF132V1 NO : 171823
	5. Test Software	Windows XP / Run PassMark Burn In Test 6.0 Pro
2.	Adapter :	FSP060-DBAB1 AC-DC 12V / 5A

Temperature rise test

Test Date: 06-17-2011

Test Product: AGD-317D

Test Site: AAEON QE Internal Lab.

Test Standard: Reference EN 61131-2(94), UL508 (94)

Temperature Measurement:

40 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: AGD-317D
Date of Calibration: 06/15/2011
Serial Number: 12A323190

Test Condition:

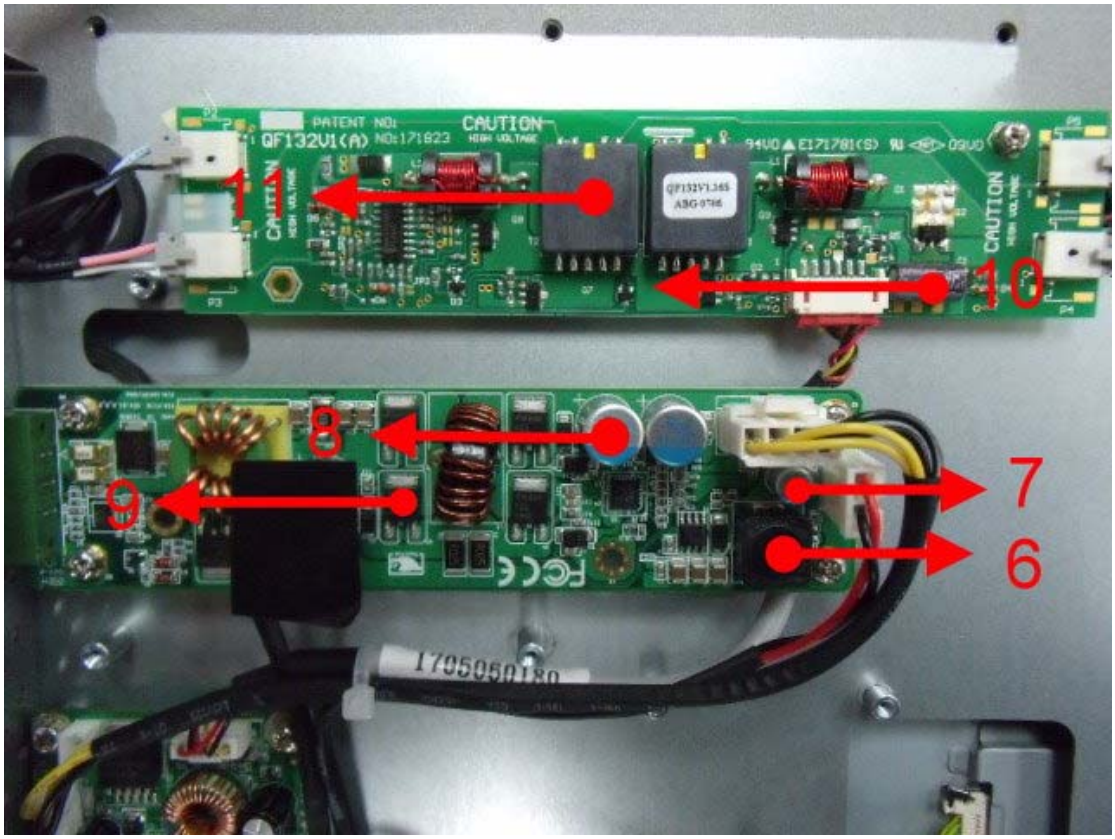
Ambient temperature: 50℃
Continuous running till thermal stability (within less than 1℃)

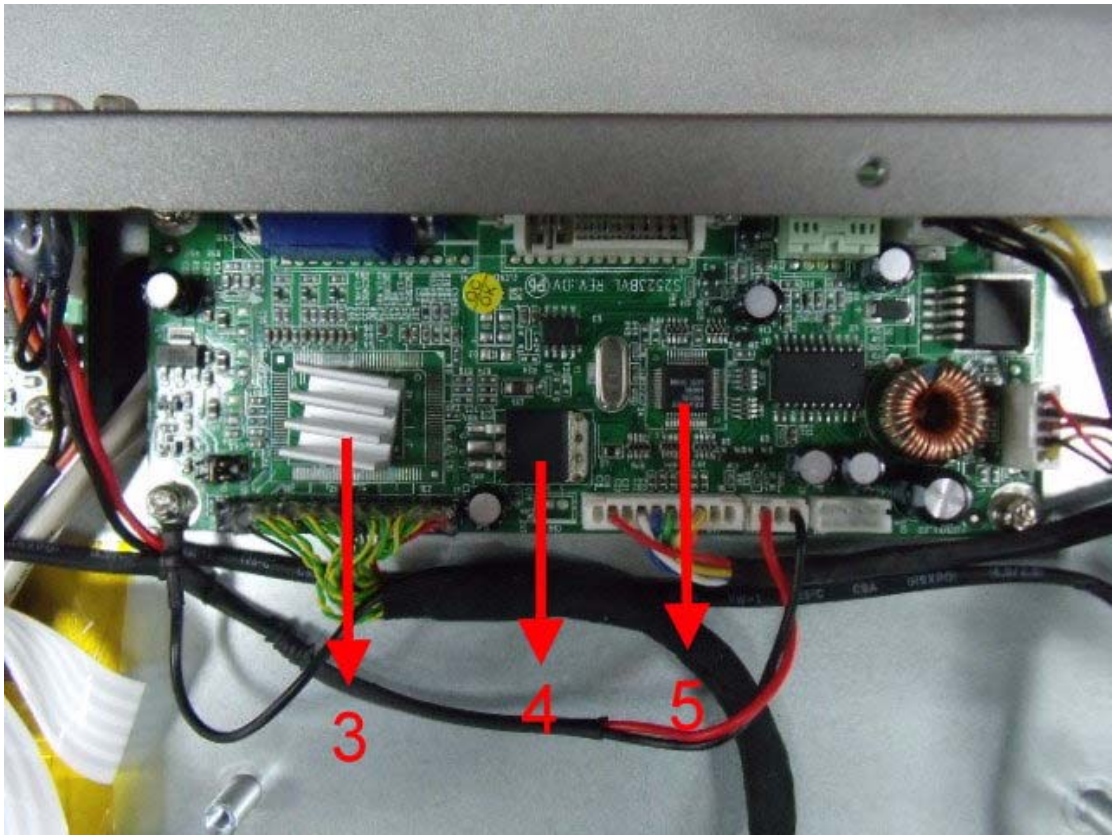
Test Software:

Windows XP / Run PassMark Burn In Test 6.0 Pro

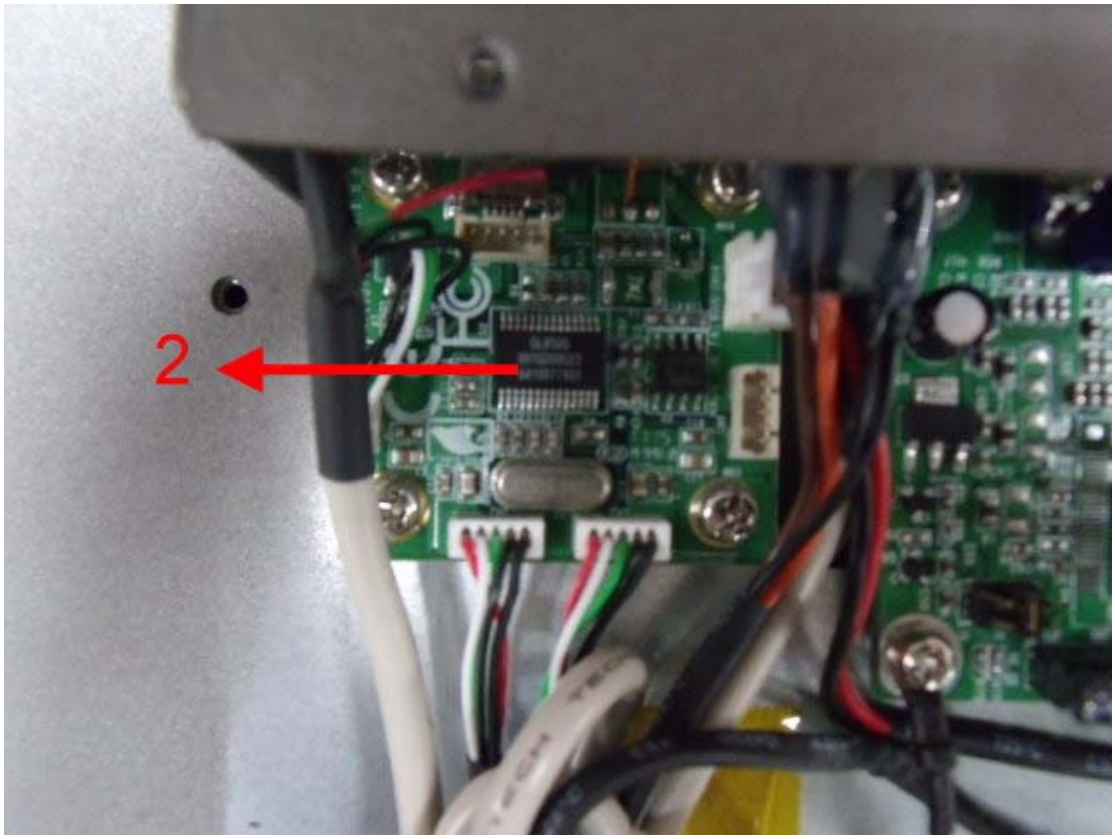
Terminal Recorder:

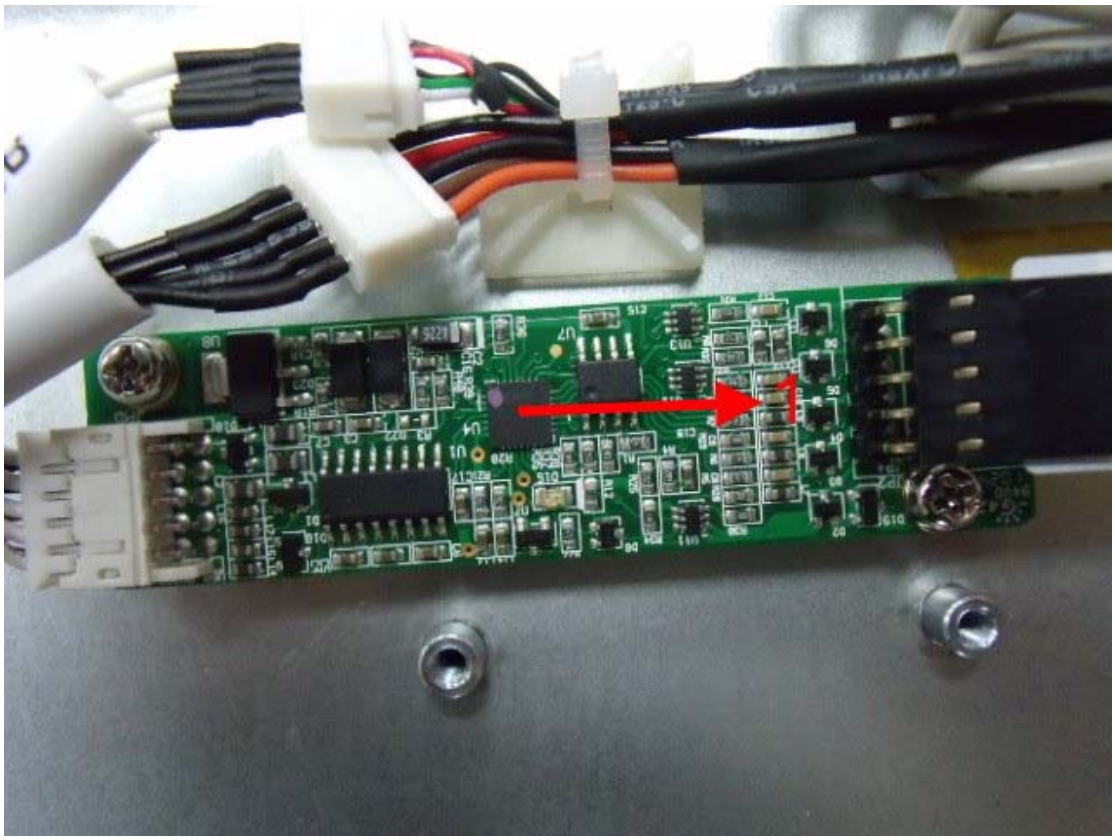
Temperature rise test





Temperature rise test





Temperature rise test

Thermal profile data:

Point \ Temp. Stage(℃)	Spec	50	25
AGD-317D			
01. U4 – EETI S458XRUP	85	68.3	43.3
02. U2 - GL850G HH1GD08G22	85	69.5	44.5
03. U6 - REALTEK RTD2555LH	85	77.9	52.9
04. U5 - AIC 1084-33GM	100	89.1	64.1
05. U4 - REALTEK RTD2120L A6M2002	85	76.2	51.2
06. L1 – 150mH	125	70.5	45.5
07. C24	125	70.2	45.2
08. C32	125	71.9	46.9
09. Q5 – 1A41AP FDD8896	130	70.8	45.8
10. C1 – 47uF/50V	105	100.3	75.3
11. T2 – QF132V 1.16S ABG0706	135	96.9	71.9
12. Control Box Inside Air Temperature	N/A	70.3	45.3
13. Control Box Surface Temperature	N/A	58.0	33.0
14. Chamber Air Temperature	N/A	49.8	24.8
Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.			

Sample Configuration & Quantity Under Test:

Quantity: 1 (AGD-317D)

Test Result:

No problem was found during the temperature rise operation test.

Temperature cycle test

Test Date: 06-14 ~ 16-2011

Test Product: AGD-317D

Test Site: AAEON QE Internal Lab.

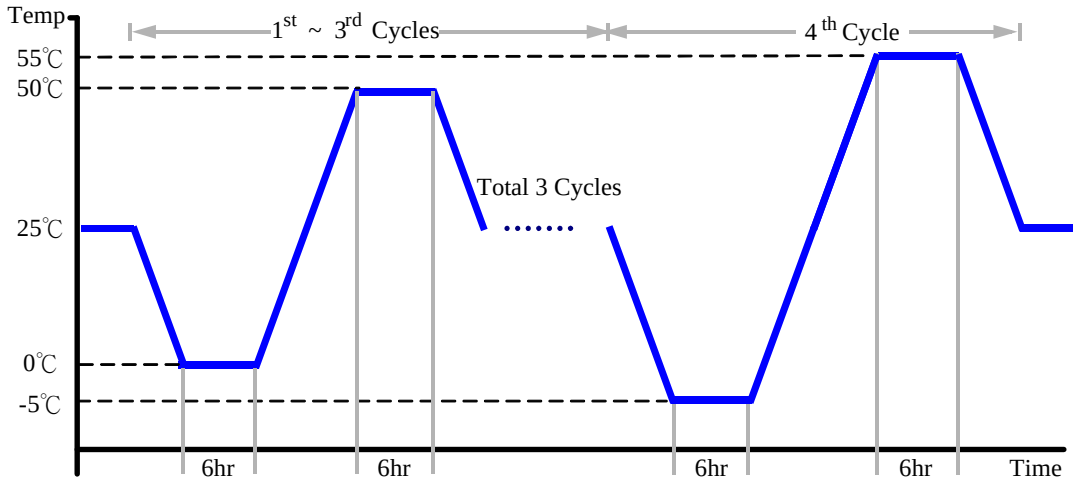
Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Test Condition:

1. Test Low Temperature: 0℃ (1~3 cycles)
   -5℃ (4th cycle)
2. Test High Temperature: 50℃ (1~3 cycles)
   55℃ (4th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2℃/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AGD-317D)

Test Result:

No problem was found during the temperature operation cycle test.

High temperature storage test

Test Date: 06-07 ~ 09-2011

Test Product: AGD-317D

Test Site: AAEON QE Internal Lab.

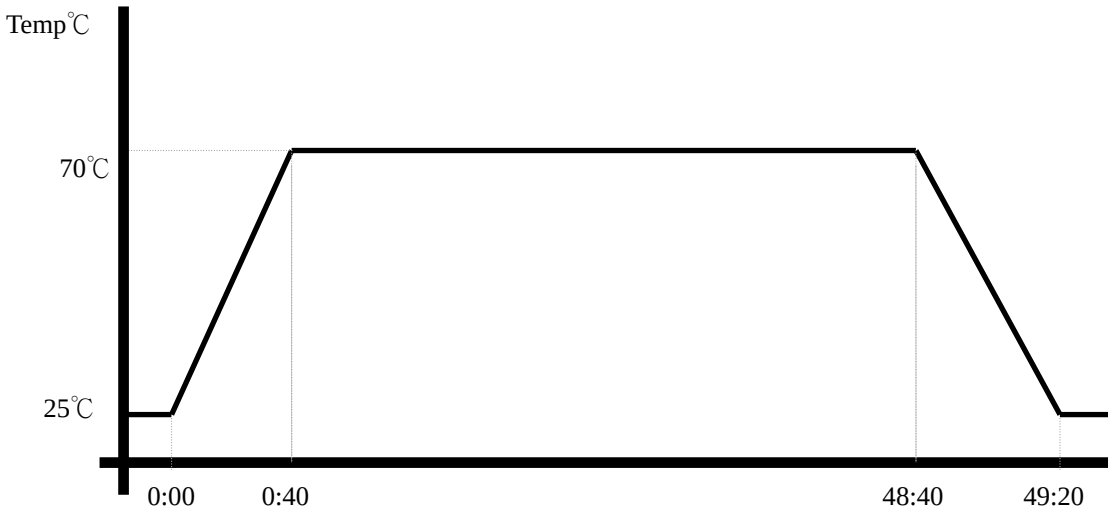
Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Testing Item:

1. Test Temperature: 70℃
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 6.0 Pro
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (AGD-317D)

Test Result:

No problem was found after the high temperature storage test.

Low temperature storage test

Test Date: 06-09 ~ 11-2011

Test Product: AGD-317D

Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Testing Item:

1. Test Temperature: -20℃
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 6.0 Pro
4. Test Environment Curve:

Sample Configuration & Quantity Under Test:
Quantity: 1 (AGD-317D)

Test Result:
No problem was found after the low temperature storage test.

Humidity test

Test Date: 06-11 ~ 13-2011

Test Product: AGD-317D

Test Site: AAEON QE Internal Lab.

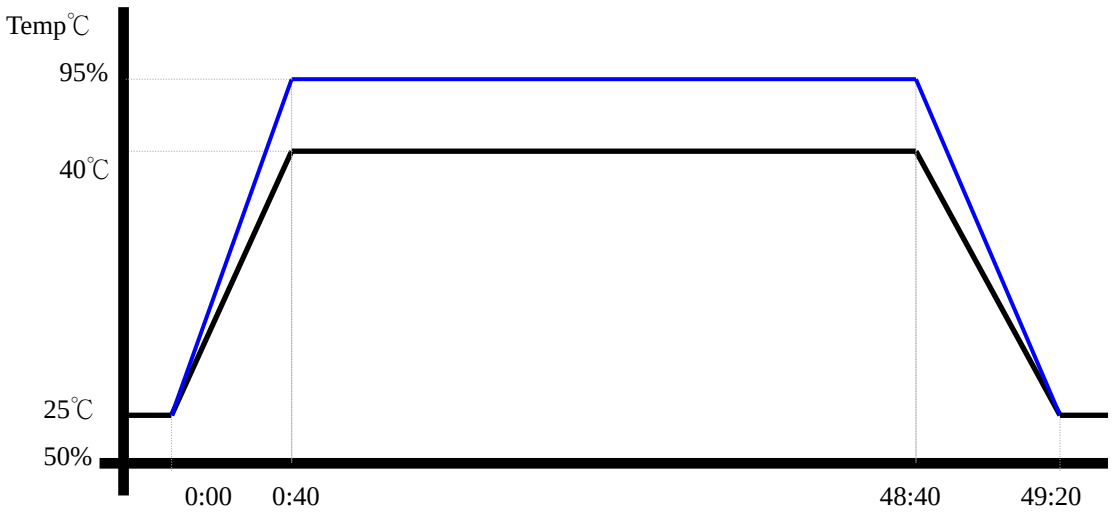
Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Testing Item:

1. Test Temperature: 40℃
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test 6.0 Pro
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (AGD-317D)

Test Result:
No problem was found after the humidity storage test.

Cold start and hot start test

Test Date: 06-13 ~ 14-2011

Test Product: AGD-317D

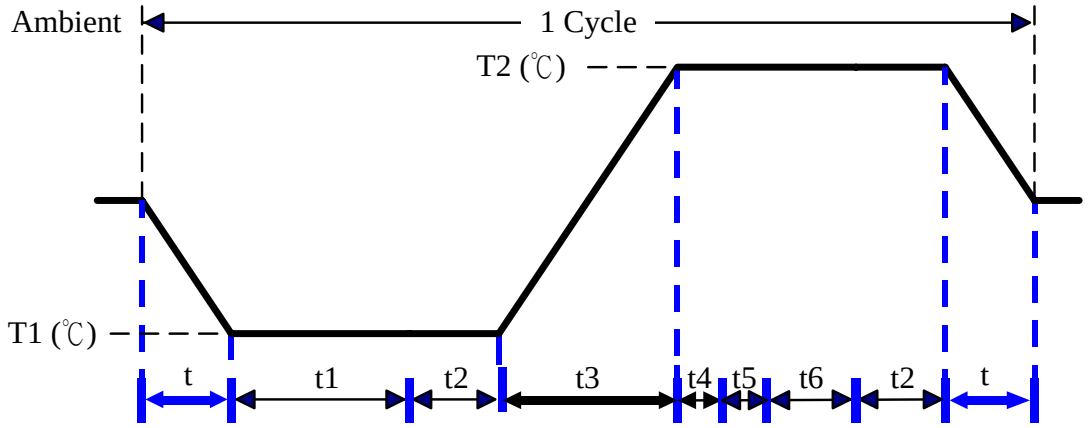
Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Test Condition:



Parameters	Description
T1	-5℃
T2	55℃
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2℃/min
n (Cycle)	1

t = temprature slope
t , t1, t6: Power Off
t2: Power on/off test 10 times (on 2 min / off 5min)
t3, t4: Run PassMark Burn In Test
t5: Win XP Software restart test 3 times
Test Software: Windows XP

Test Result:

a. No problem was found during the cold start test.
b. No problem was found during the hot start test.